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**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 4589.1-2006

Replacing GB/T 4589.1-1989

**Semiconductor devices -- Part 10: Generic specification for
discrete devices and integrated circuits**

半导体器件 第10部分：分立器件和集成电路总规范

(English Translation)

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Table of Contents

What this standard covers	1
Document data	2

What this standard covers

This standard applies to semiconductor devices (discrete devices and integrated circuits, including multi-chip integrated circuits, hybrid circuits, but not including) the total specification. This specification defines the IECQ system used within the total quality assessment procedures, and gives the following aspects of the general principle: electrical characteristics side test methods, climatic and mechanical tests, endurance test. This specification constitutes the International Electrotechnical Commission Quality Assessment System for Electronic 7ri devices (IECQ) part.

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